

**Product Summary**

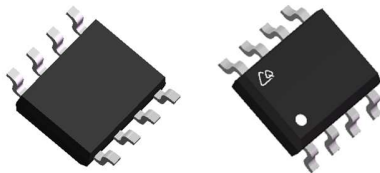
**Description and Applications**

V(BR)DSS	RDS(ON) max	ID max
-30V	<16mΩ @ VGS = -10V	-10A
	<19mΩ @ VGS = -4.5V	

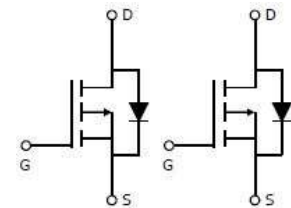
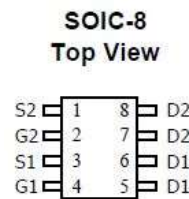
The CQS03DP16 uses advanced trench technology to provide excellent RDS(ON). This device is suitable for use as a load switch or other general applications.

RoHS and Halogen-Free Compliant.

**View and Internal Schematic Diagram**



SO8



Internal Schematic

**Marking Information**

SO8



PN=03DP16  
F=Fab location  
A=Assembly location  
Y=Year  
W=Week  
LT=Lot sequence

**Ordering Information**

Part Number	Case	Packaging
CQS03DP16	SO8	3,000/Tape & Reel

**Maximum Ratings** (@TA = +25°C unless otherwise specified.)

Parameters	Symbol	Max	Units
Drain-Source Voltage	VDSS	-30	V
Gate-Source Voltage	VGSS	±20	V
Continuous Drain Current	ID	TA = +25°C -10	A
		TA = +70°C -7.9	
Pulsed Drain Current <sup>C</sup>	IDM	-40	A
Power Dissipation <sup>B</sup>	PD	TA = +25°C 2.5	W
		TA = +70°C 1.6	
Operating and Storage Temperature Range	TJ, TG	-55 to+150	°C

**Thermal Characteristics**

Characteristic		Symbol	Typ	Max	Unit
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{\theta JA}$	37	49	$^{\circ}C/W$
Maximum Junction-to-Ambient <sup>A D</sup>	Steady-State		62	78	$^{\circ}C/W$
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	16	24	$^{\circ}C/W$

**Electrical Characteristics (@ $T_A = +25^{\circ}C$  unless otherwise specified.)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D = -250\mu A, V_{GS} = 0V$	-30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -30V, V_{GS} = 0V$			-1	$\mu A$
		$T_J = 55^{\circ}C$			-5	
$I_{GSS}$	Gate-Body leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1.1	-1.6	-2.1	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS} = -10V, I_D = -9A$		11.8	16	m $\Omega$
		$T_J = 125^{\circ}C$		16.5	23	
		$V_{GS} = -4.5V, I_D = -9A$		15	21.5	m $\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = -5V, I_D = -9A$		39		S
$V_{SD}$	Diode Forward Voltage	$I_S = -4.1A, V_{GS} = 0V$		-0.77	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-3.2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance			1769		pF
$C_{oss}$	Output Capacitance	$V_{GS} = 0V, V_{DS} = -15V,$ $f = 1MHz$		234		pF
$C_{rss}$	Reverse Transfer Capacitance			205		pF
$R_g$	Gate resistance	$V_{GS} = 0V, V_{DS} = 0V,$ $f = 1MHz$		4.3	9	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10V)$	Total Gate Charge	$V_{GS} = -10V, V_{DS} = -15V,$ $I_D = -9A$		36.8		nC
$Q_{gs}$	Gate Source Charge			6.5		nC
$Q_{gd}$	Gate Drain Charge			7.2		nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS} = -10V, V_{DS} = -15V,$ $R_L = 1.67\Omega, R_{GEN} = 3\Omega$		8		ns
$t_r$	Turn-On Rise Time			42.8		ns
$t_{D(off)}$	Turn-Off Delay Time			49.5		ns
$t_f$	Turn-Off Fall Time			63		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F = -9.0A, dI/dt = 100A/\mu s$		15		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F = -9.0A, dI/dt = 100A/\mu s$		5		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 1oz. Copper, in a still air environment with  $T_A = 25^{\circ}C$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)} = 150^{\circ}C$ , using  $\leq 10s$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)} = 150^{\circ}C$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J = 25^{\circ}C$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $< 300\mu s$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 1oz. Copper, assuming a maximum junction temperature of  $T_{J(MAX)} = 150^{\circ}C$ . The SOA curve provides a single pulse rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERIS

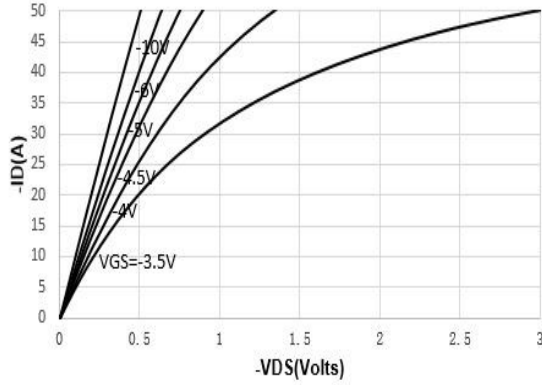


Figure 1: On-Region Characteristics (Note E)

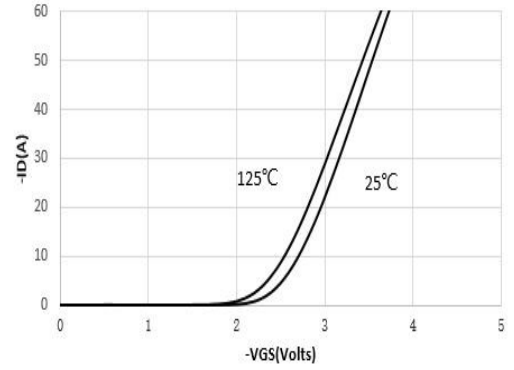


Figure 2 Transfer Characteristics (Note E)

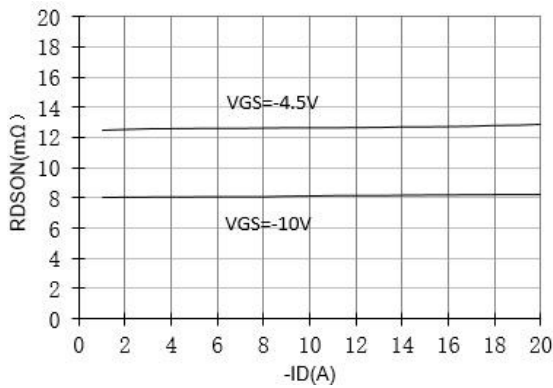


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

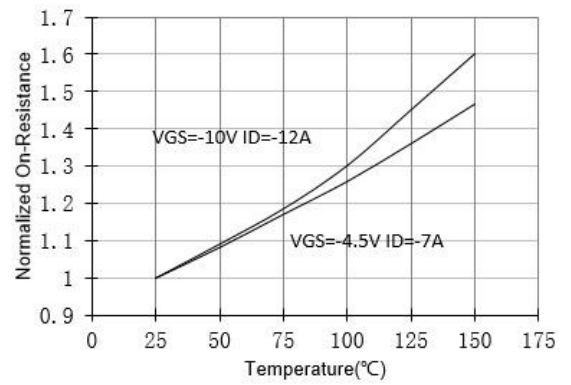


Figure 4: On-Resistance vs. Junction Temperature (Note E)

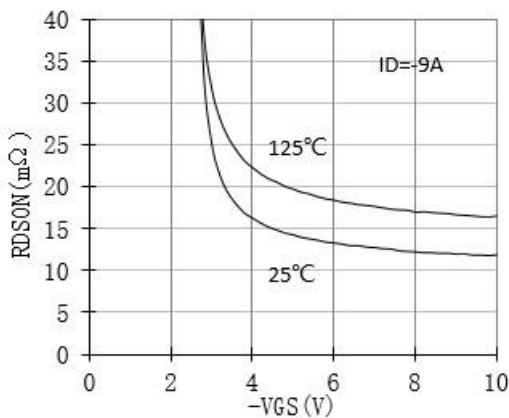


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

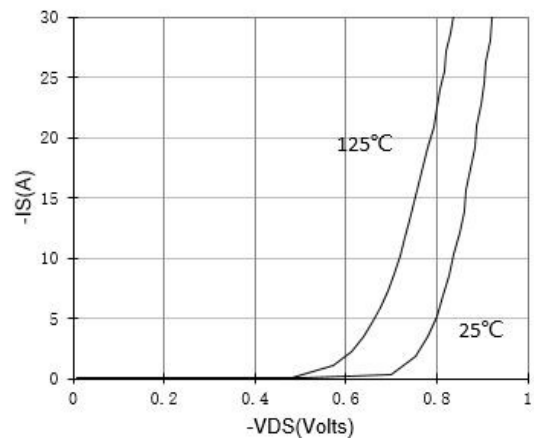


Figure 6: Body-Diode Characteristics (Note E)

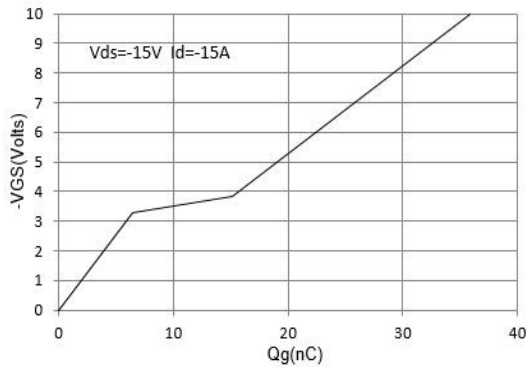


Figure 7: Gate-Charge Characteristics

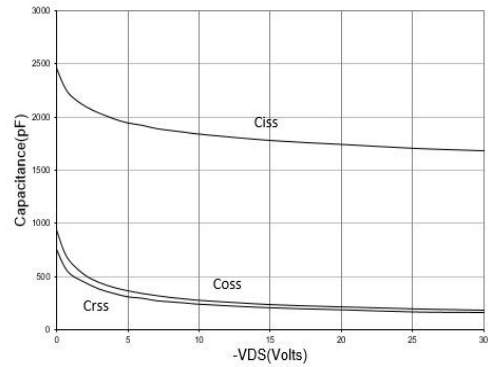


Figure 8: Capacitance Characteristics

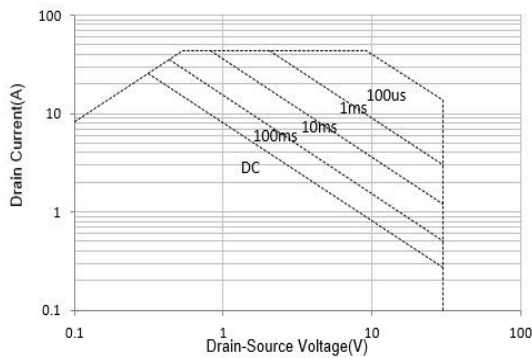


Figure 9: Maximum Forward Biased Safe Operating Area

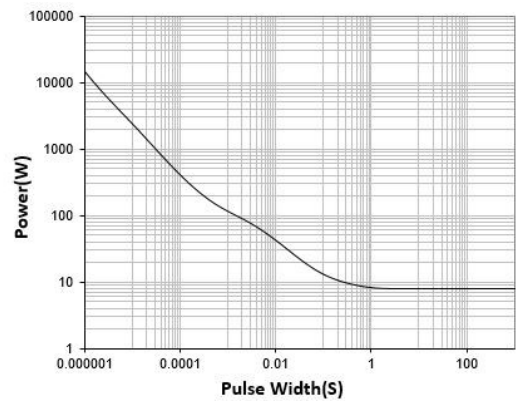


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

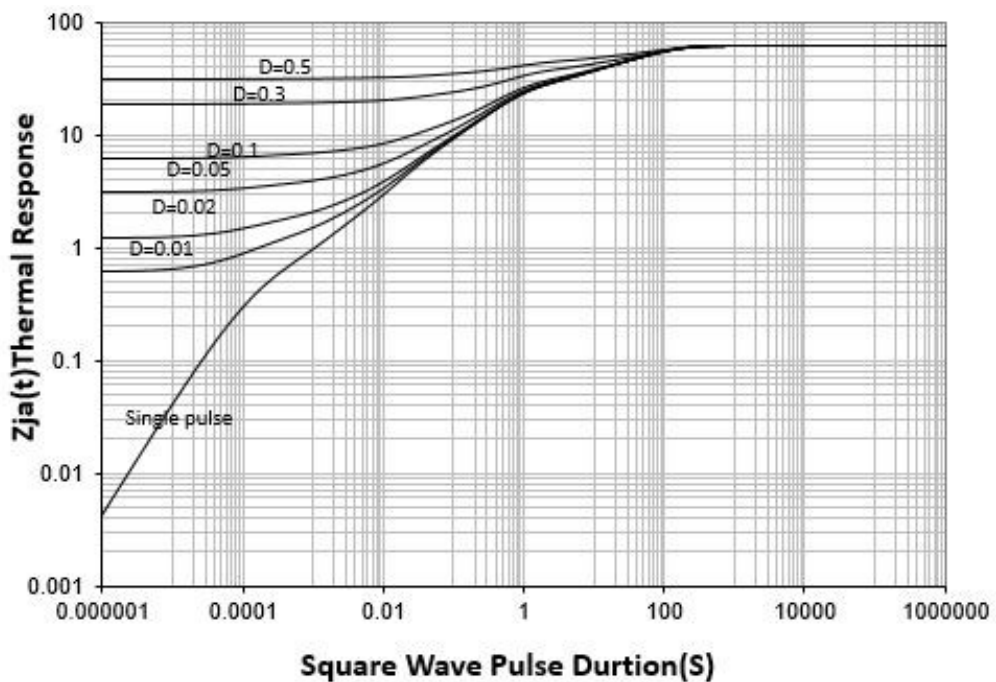


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)

单击下面可查看定价，库存，交付和生命周期等信息

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